

 View PDFAccess through **your institution**[Purchase PDF](#)

Computer Standards & Interfaces
Volume 33, Issue 2, February 2011, Pages 191-200

Detection and characterization of defects using GMR probes and artificial neural networks

O. Postolache  , H. Geirinhas Ramos , A. Lopes Ribeiro 

[Show more](#) 

 Outline |  Share  Cite

<https://doi.org/10.1016/j.csi.2010.06.011>

[Get rights and content](#)

Abstract

This work presents an eddy-current testing system based on a giant magnetoresistive (GMR) sensing device. Non-destructive tests in aluminum plates are applied in order to extract information about possible defects: cracks, holes and other mechanical damages. Eddy-current testing (ECT) presents major benefits such as low cost, high checking speed, robustness and high sensitivity to large classes of defects. Coil based architecture probes or coil-magnetoresistive probes are usually used in ECT. In our application the GMR sensor is used to detect a magnetic field component parallel to a plate surface, when an excitation field perpendicular to the plate is imposed. A neural network processing architecture, including a multilayer perceptron and a competitive neural network, is used to classify defects using the output amplitude of the eddy-current probe (ECP) and its operation frequency. The crack detection, classification and estimation of the geometrical characteristics, for different classes of defects, are described in the paper.

 Previous

Next 
FEEDBACK 

Keywords

Non-destructive testing; Eddy currents; Magnetoresistive sensor; Neural network classifier

[Special issue articles](#)

[Recommended articles](#)

[Citing articles \(35\)](#)



Octavian A. Postolache was born in Piatra Neamt, Romania, on July 29, 1967. He received the PhD degree in Electrical Engineering from the Faculty of Electrical Engineering, “Gh. Asachi” Technical University of Iasi, Iasi, Romania, in 1999. In 1992, he joined the Faculty of Electrical Engineering, Department of Electrical Measurements and Electrical Materials, Technical University of Iasi, where he worked for nine years as a Lecturer and an Assistant Professor. In 2000, he started working as a PhD Researcher at the Instituto Superior Técnico and Instituto de Telecomunicações, Lisbon, Portugal, where he has been involved in different projects in the area of instrumentation. His main research interests concern smart sensors for environmental and biomedical applications, sensor and algorithms implementation for non-destructive testing, distributed instrumentation, sensor networks and computational intelligence implementation in automated measurement systems.



Helena Maria G. Ramos was born in Lisbon, Portugal, on October 1957. She received the Ing. Degree in Electrical and Computer Engineering in 1980, the M.Sc., PhD. and Aggregation Degrees in Electrical and Computer Engineering from IST, Technical University of Lisbon in 1987, 1995 and 2006 respectively. She is an Associate Professor in IST where she is a member of the teaching staff since 1980. She is a member of the Instrumentation and Measurement Group at Instituto de Telecomunicações. Her main research interests include NDT of conductive materials, PC based instrumentation, measurement interfaces, ADC testing, transducers and ferromagnetic materials modeling. She was and still is involved in research in many national and international projects in these areas.



A. Lopes Ribeiro (M'90) was born in Lisbon, Portugal, on April 8, 1950. He received the Diploma degree in electrical engineering and the Ph.D. degree in electrical and computer engineering from the Instituto Superior Técnico (IST), Technical University of Lisbon (UTL), Lisbon, in 1973 and 1990, respectively. In 1977, he joined the Department of Electrical and Computer Engineering, IST/UTL, where he has been a Member of Teaching Staff. In 1991, he joined the Instituto de Telecomunicações, UTL. His research interests include the instrumentation and electric measurement and numerical modeling of electrical and optoelectronic components. Dr. Lopes Ribeiro is a member of the International Compumag Society.

[View full text](#)

Copyright © 2010 Elsevier B.V. All rights reserved.



[About ScienceDirect](#)

[Remote access](#)

[Shopping cart](#)

[Advertise](#)

[Contact and support](#)

[Terms and conditions](#)

[Privacy policy](#)

We use cookies to help provide and enhance our service and tailor content and ads. By continuing you agree to the **use of cookies**.
Copyright © 2021 Elsevier B.V. or its licensors or contributors. ScienceDirect® is a registered trademark of Elsevier B.V.
ScienceDirect® is a registered trademark of Elsevier B.V.

